

Notice of References Cited			Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner			Art Unit	2166	Page 1 of 1
SHEW-FEN LIN					

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*	B	US-6,990,333	01-2006	Andrew et al.	455/414.1
*	C	US-7,243,130	07-2007	Horvitz et al.	709/207
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	L	US-			
	M	US-			

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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a))
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